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# Table of Contents

## Keynote Talks

---

<b>On-line test of embedded systems: which role for functional test?</b>	<b>1</b>
<i>Matteo Sonza Reorda</i>	
<b>TSV Based 3D Stacked ICs: Opportunities and Challenges</b>	<b>2</b>
<i>Said Hamdioui</i>	
<b>Vertical Slit Transistor based Integrated Circuits (VeSTICs)</b>	<b>3</b>
<i>Andrzej Pfitzner</i>	

## Embedded Tutorials

---

<b>3D Integration: Opportunities, Design Challenges and Approaches.</b>	<b>4</b>
<i>Uwe Knöchel</i>	
<b>Asynchronous Circuit Design: From Basics to Practical Applications.</b>	<b>5</b>
<i>Eckhard Grass, Milos Krstic, Xin Fan, Steffen Zeidler</i>	
<b>Automated Synthesis and Design Error Repair of Systems.</b>	<b>6</b>
<i>Georg Hofferek</i>	
<b>Fault management in an IEEE P1687 (IJTAG) environment.</b>	<b>7</b>
<i>Erik Larsson, Konstantin Shubin</i>	

## Poster Session I

---

<b>Design Methodology for Fault Tolerant ASICs.</b>	<b>8</b>
<i>Petrovic, Vladimir; Ilic, Marko; Schoof, Gunter; Stamenkovic, Zoran</i>	
<b>Selective redundancy to improve reliability and to slow down delay degradation due to gate oxide breakdown.</b>	<b>12</b>
<i>Saemrow, Hagen; Cornelius, Claas; Gorski, Philipp; Tockorn, Andreas; Timmermann, Dirk</i>	
<b>Synthesis of Petri Nets into FPGA with Operation Flexible Memories.</b>	<b>16</b>
<i>Bukowiec, Arkadiusz; Adamski, Marian</i>	
<b>An evaluation of the application dependent FPGA test method.</b>	<b>22</b>
<i>Rozkovec, Martin; Jenicek, Jiri; Novak, Ondrej</i>	
<b>AGATE – Towards Designing a Low-power Chip Multithreading Processor for Mobile Software Defined Radio Systems.</b>	<b>26</b>
<i>Marcinek, Krzysztof; Pleskacz, Witold A.</i>	
<b>Improving the Iterative Power of Resynthesis.</b>	<b>30</b>
<i>Fiser, Petr; Schmidt, Jan</i>	
<b>NAND/NOR Gate Polymorphism in Low Temperature Environment.</b>	<b>34</b>
<i>Ruzicka, Richard; Simek, Vaclav</i>	
<b>Current Sensing Completion Detection In Dual-Rail Asynchronous Systems.</b>	<b>38</b>
<i>Nagy, Lukas; Stopjakova, Viera</i>	
<b>Power Constraint Testing for Multi-Clock Domain SoCs Using Concurrent Hybrid BIST.</b>	<b>42</b>
<i>Haghighyan, Mohammadhashem; Safari, Saeed; Navabi, Zainalabedin</i>	
<b>An Interconnect for MPSoC Monitoring and Parameter Optimization.</b>	<b>46</b>
<i>Bouajila, Abdelmajid; Lakhtel, Abdallah; Zeppenfeld, Johannes; Stechele, Walter; Herkersdorf, Andreas</i>	

## Session 1A: Processor Architectures

---

- Design Techniques for Increasing Performance and Resource Utilization of Reconfigurable Soft CPUs.** 50  
*Wold, Alexander; Koch, Dirk; Torresen, Jim*
- An Automated Infrastructure for Real-Time Monitoring of Multi-Core Systems-on-Chip.** 56  
*Kornaros, George; Christoforakis, Ioannis; Astrinaki, Maria*
- The Architecture and the Technology Characterization of an FPGA-based Customizable Application-Specific Vector Processor.** 62  
*Sykora, Jaroslav; Kohout, Lukas; Bartosinski, Roman; Kafka, Leos; Danek, Martin; Honzik, Petr*

## Session 1B: Analog and RF Desing

---

- LC-VCO Design Automation Tool for Nanometer CMOS Technology.** 68  
*Siwiec, Krzysztof; Borejko, Tomasz; Pleskacz, Witold*
- A Gigabit Fully Integrated Plastic Optical Fiber Receiver for a RC-LED Source.** 74  
*Atef, Mohamed; Swoboda, Robert; Zimmermann, Horst*
- Low Phase Noise Ka-Band Voltage Controlled Oscillator Using 0.15 um GaAs pHEMT Technology.** 79  
*Kao, H. L.; Shih, S. P.; Yeh, C. S.; Chang, L. C.*

## Session 2A: NoC Simulation and Test

---

- A Simulation Framework for 3-Dimension Networks-on-Chip with Different Vertical Channel Density Configurations.** 83  
*Ying, Haoyuan; Jaiswal, Ashok; Abdel-Ghany, Mohamed Ahmed; Hollstein, Thomas; Hofmann, Klaus*
- HLS-DoNoC: High-Level Simulator for Dynamically Organizational NoCs.** 89  
*Guang, Liang; Nigussie, Ethiopia; Plosila, Juha; Isoaho, Jouni; Tenhunen, Hannu*
- Low-Area Boundary BIST Architecture for Mesh-like Network-on-Chip.** 95  
*Raik, Jaan; Govind, Vineeth*

## Session 2B: Analog, RF Design and Test

---

- Test and configuration architecture of a sub-THz CMOS detector array.** 101  
*Földesy, Péter; Gergelyi, Domonkos; Fúzy, Csaba; Károlyi, Gergely*
- Automatic Integration of Hardware Descriptions into System-Level Models.** 105  
*Görgen, Ralph; Oetjens, Jan-Hendrik; Nebel, Wolfgang*
- Multisine Signal Generation Method for a Bioimpedance Measurement Device.** 111  
*Pesonen, Vadim; Gorev, Maksim; Ellervee, Peeter*

## Session 4A: Fault Tolerance

---

- Radiation-Tolerant Combinational Gates – An Implementation Based Comparison.** 115  
*Savulimedu Veeravalli, Varadan; Steininger, Andreas*
- Monitoring-Driven HW/SW Interrupt Overload Prevention for Embedded Real-Time Systems.** 121  
*Strnadel, Josef*
- Efficient Link-level Error Resilience in 3D NoCs.** 127  
*Pasca, Vladimir; Rehman, Saif-Ur; Anghel, Lorena; Benabdenbi, Mounir*

## Session 4B: Security

---

- The Design of Dependable Flexible Multi-Sensory System-on-Chips for Security Applications.** 133  
*Zhao, Yong; Kerkhoff, Hans G.*
- System Side-Channel Leakage Emulation for HW/SW Security Coverification of MPSoCs.** 139  
*Krieg, Armin; Grinschgl, Johannes; Steger, Christian; Weiss, Reinhold; Bock, Holger; Haid, Josef*
- Security Properties of Oscillator Rings in True Random Number Generators.** 145  
*Wold, Knut; Petrovic, Slobodan*

## Session 5A: Short Papers I

---

- An FPGA Algorithm Development for an Improved Servo-Loop Method.** P 1C  
*Židek, Jan; Mullane, Brendan; Šubrt, Ondřej; Martinek, Pravoslav*
- Differential Evolutionary Optimization Algorithm applied to ESD MOSFET model fitting problem.** 155  
*Napravnik, Tomas; Kote, Vlastimil; Molata, Vladimir; Jakovenko, Jiri*
- A three-dimensional DRAM using floating body cell in FDSOI devices.** 159  
*Liu, Xuelian*
- CDMA Technique for Network-on-Chip.** 163  
*El Badry, Ahmed; Abd El Ghany, Mohamed*

## Session 5B: Short Papers II

---

- Application of IDDT test towards increasing SRAM reliability in nanometer technologies.** 167  
*Gyepes, Gabor; Arbet, Daniel; Brenkus, Juraj; Stopjakova, Viera*
- Evaluation of Susceptibility of FPGA-based Circuits to Fault Injection Attacks Based on Clock Glitching.** 171  
*Korczyk, Jakub; Krasniewski, Andrzej*
- D&T Presenter – Electronic Interactive System for Design and Test Education.** 175  
*Martinek, Valter; Hlatký, Matej; Gramatová, Elena*
- A 1V, Low Power, High-Gain, 3 – 11 GHz Double-Balanced CMOS Sub-Harmonic Mixer.** 179  
*Fegghi, Rouhollah; Naseh, Sasan*

## Poster Session II

---

- Reduction of Complex Safety Models based on Markov Chains.** 183  
*Kohlik, Martin; Kubátová, Hana*
- Generation of SystemC/TLM code from UML/MARTE sequence diagrams for verification.** 187  
*Ebeid, Emad Samuel Malki; Quaglia, Davide; Fummi, Franco*
- A 512 kb SRAM in 65nm CMOS with Divided Bitline and Novel Two-stage Sensing Technique.** 191  
*Zheng, Xiang; Liu, Ming; Chen, Hong; Cao, Huamin; Wang, Cong; Gao, Zhiqiang*
- OBIST Strategy versus Parametric Test - Efficiency in Covering Catastrophic Faults in Active Analog Filters.** 193  
*Arbet, Daniel; Gyepes, Gabor; Brenkus, Juraj; Stopjakova, Viera*
- Optimised Power Supply Unit Design.** 195  
*Pospisilik, Martin; Adamek, Milan*
- Lightweight Cipher Resistivity against Brute-Force Attack: Analysis of PRESENT.** 197  
*Pospíšil, Jan; Novotný, Martin*
- VHDL Visualizer: HDL Model Visualization with Simulation-Based Verification.** 199  
*Macko, Dominik; Jelemenská, Katarina*
- Measurement of on-Chip Temperature and Crosstalk using Ring Oscillators in FPGA Devices.** 201  
*Gag, Martin; Wegner, Tim; Waschki, Ansgar; Timmermann, Dirk*

**Adaptive Voltage Scaling by In-Situ Delay Monitoring for an Image Processing Circuit.** 205  
*Wirnshofer, Martin; Heiß, Leonhard; Kakade, Anil Narayan; Pour Aryan, Nasim; Georgakos, Georg; Schmitt-Landsiedel, Doris*

**Effective RT-Level Software-Based Self-Testing of Embedded Processor Cores.** 209  
*Sha'afi Kabiri, Parisa; Navabi, Zainalabedin*

### Session 6A: ASIC/FPGA Design

---

**High speed FPGA implementation of Hough transform for real-time applications.** 213  
*Voudouris, Liberis; Nikolaidis, Spiridon; Rjoub, Abdoul*

**Generation of Non-Overlapping Clock Signals without using a Feedback Loop.** 219  
*Spilka, Ronald; Hilber, Gerald; Rauchenecker, Andreas; Gruber, Domink; Sams, Michael; Ostermann, Timm*

**Design and Implementation of High-Performance High-Valency** 224  
*Ling Adders. Kocak, Taskin; Patil, Preeti*

### Session 6B: Test Generation and Fault Detection

---

**A New SAT-based ATPG for Generating Highly Compacted Test Sets.** 230  
*Eggersglüß, Stephan; Krenz-Baath, Rene; Glowatz, Andreas; Hapke, Friedrich; Drechsler, Rolf*

**Multiple Stuck-at-Fault Detection Theorem.** 236  
*Ubar, Raimund; Kostin, Sergei; Raik, Jaan*

**Genetic Method for Compressed Skewed-Load Delay Test Generation.** 242  
*Dobai, Roland; Baláz, Marcel*

### Poster Session III

---

**Auto-Calibration Techniques in Built-in Jitter Measurement Circuit.** 248  
*Cheng, Chih-Ping; Liu, Jen-Chieh; Cheng, Kuo-Hsing*

**Low Power Balun Design for 1.575 GHz in 90 nm CMOS Technology.** 250  
*Gradzki, Jacek*

**Digital-Driven Formal Analog Verification for Asynchronously Feed-Backed Circuitries.** 254  
*Uygur, Gürkan; Sattler, Sebastian Michael*

**Bounded Model Checking of Contiki Applications.** 258  
*Vörtler, Thilo; Rülke, Steffen; Hofstedt, Petra*

**Low Power Scan by Partitioning and Scan Hold.** 262  
*Arvaniti, Efi; Tsiatouhas, Yiorgos*

**A User-level Library for Fault Tolerance on Shared Memory Multicore Systems.** 266  
*Mushtaq, Hamid; Al-Ars, Zaid; Bertels, Koen*

**A Low Voltage Sigma Delta Modulator for Temperature Sensor.** 270  
*Juan, Yi-Hsiang; Huang, Hong-Yi; Luo, Ching-Hsing*

**Developing a New Phase Noise Estimation Technique Based on Time Varying Model.** 274  
*Izadpanah, Saber; Kargaran, Ehsan; Nabovati, Hooman*

**Lightweight benchmarking of platforms for network traffic processing.** 278  
*Korcek, Pavol; Zadnik, Martin*

**A New Analog Output Buffer for Data Driver of Active Matrix Displays Using Low-Temperature Polycrystalline Silicon Thin-Film Transistors.** 284  
*Pappas, Ilias; Siskos, Stylianos; Hatzopoulos, Alkis A.*

## **Session 8A: On-line Test and Self-Repair**

---

- Combining On-Line Fault Detection and Logic Self Repair.** 288  
*Vierhaus, Heinrich T.; Koal, Tobias; Ulbricht, Markus*
- Online Self-Checking and Correction for Crosstalk-Induced Timing Errors on VLSI Interconnects.** 294  
*Lai, Ping-Liang; Huang, Der-Chen*
- On Test Time Reduction Using Pattern Overlapping, Broadcasting and On-Chip Decompression.** 300  
*Chloupek, Martin; Novak, Ondrej; Jenicek, Jiri*

## **Session 8B: Test and Reliability of Microprocessors**

---

- A SBST Strategy to Test Microprocessors' Branch Target Buffer.** 306  
*Sanchez, Ernesto; Bernardi, Paolo; Ciganda, Lyl; Grosso, Michelangelo; Sonza Reorda, Matteo*
- An Adaptive Self-Test Routine for In-Field Diagnosis of Permanent Faults in Simple RISC Cores.** 312  
*Schölzel, Mario; Koal, Tobias; Vierhaus, Heinrich Theodor*
- CIVA: Custom Instruction Vulnerability Analysis Framework.** 318  
*Azarpeyvand, Ali; E.Salehi, Mostafa; Fakhraie, Seid Mehdi*

## **Session 9A: Design Verification**

---

- Automated Debugging from Pre-Silicon to Post-Silicon.** 324  
*Dehbashi, Mehdi; Fey, Goerschwin*
- On the use of assertions for embedded-software dynamic verification.** 330  
*Di Guglielmo, Giuseppe; Di Guglielmo, Luigi; Fummi, Franco; Pravadelli, Graziano*
- Test Platform for Fault Tolerant Systems Design Qualities Verification.** 336  
*Straka, Martin; Miculka, Lukas; Kastil, Jan; Kotasek, Zdenek*

## **Session 9B: Reliability Challenges in Nano-Scale Technology**

---

- Reliability Challenges in Avionics due to Silicon Aging.** 342  
*Mesgarzadeh, Behzad; Söderquist, Ingemar; Alvandpour, Atila*
- BTI Impacts on Logical Gates in Nano-scale CMOS Technology.** 348  
*Khan, Seyab; Hamdioui, Said; Cathoor, Francky; Halil, Kukner; Raghavan, Praveen*
- On-Chip Aging Sensor to Monitor NBTI Effect in Nano-Scale SRAM.** 354  
*Vargas, Fabian; Ceratti, Arthur; Copetti, Tomas; Bolzani, Leticia*

## **Session 10A: Physical Design**

---

- Complementary Edge Alignment and Digital Output Signal Speed-Up CMOS Positive Feedback Latches.** 360  
*Milovanović, Vladimir; Zimmermann, Horst*
- Reconfigurable Time Interval Measurement Circuit Incorporating a Programmable Gain Time Difference Amplifier.** 366  
*Alahmadi, Ahmed Naif M.; Russell, Gordon; Yakovlev, Alex*

## **Session 10B: Industrial Papers**

---

<b>Efficient Digital Design for Automotive Mixed-Signal ASICs Using Simulink.</b>	<b>372</b>
<i>Mauderer, Andreas; Freier, Marvin; Oetjens, Jan-Hendrik; Rosenstiel, Wolfgang</i>	
<b>VARMA - Variability Modelling and Analysis Tool.</b>	<b>378</b>
<i>Russell, Gordon; Burns, Frank; Yakovlev, Alex</i>	
<b>Author Index</b>	<b>385</b>